

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.	:	10/566,116	Confirmation No. 3700
Applicant	:	Akihisa Inoue et al.	
371(c) Date	:	January 24, 2006	
Art Unit	:	1742	
Examiner	:		
Customer No.	:	00270	
Title	:	SPUTTERING TARGET AND METHOD FOR PRODUCTION THEREOF	

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

In compliance with their duty to disclose under 37 CFR §1.56(a), Applicants and their attorneys enclose a form PTO-1449 and copies of the foreign and other documents listed therein.

The cited references were cited in the International Search Report for International Application No. PCT/JP04/10361 or are related U.S. patent documents.

The Examiner is respectfully requested to consider the cited documents and to make the same of record in the file of the present application.

In the event that a fee for the Information Disclosure Statement is required, please charge the fee to our Deposit Account No. 08-3040.

Respectfully submitted,
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Form PTO-1449 U.S. Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT	Atty. Docket No. OGOSH44USA	Serial No. 10/566,116
	Applicant: Akihisa Inoue et al.	
	371 (c) Date: January 24, 2006	Group Art Unit: 1742

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Subclass
	5,785,828	7/1998	Yamada et al.		
	5,882,493	3/1999	Iwasaki et al.		
	6,127,016	10/2000	Yamada et al.		
	6,280,684 B1	8/2001	Yamada et al.		
	6,503,592 B1	1/2003	Yamada et al.		
	2003/0008168 A1	1/2003	Shibuya et al.		

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation	
				Yes	No
	JP 2000-144380	5/2000	Japan	Abstract only	X
	JP 2002-212716	7/2002	Japan	Abstract only	X
	JP 05-017868	1/1993	Japan	Abstract only	X
	JP 2000-207725	7/2000	Japan	Abstract only	X
	JP 2002-069550	3/2002	Japan	Abstract only	X
	JP 2002-363615	12/2002	Japan	Abstract only	X

Other Documents (including Author, Title, Date, Pertinent Pages, Etc.)

Examiner	Date Considered

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.